

CY62148BN MoBL[®] 4-Mbit (512K x 8) Static RAM

Features

- 4.5V–5.5V operation
- Low active power
 - Typical active current: 2.5 mA @ f = 1 MHz
 Typical active current:12.5 mA @ f = fmax
- Low standby current
- Automatic power down when deselected
- TTL-compatible inputs and outputs
- Easy memory expansion with CE and OE features
- CMOS for optimum speed and power
- Available in standard Pb-free and non Pb-free 32-lead (450-mil) SOIC and 32-lead TSOP II packages

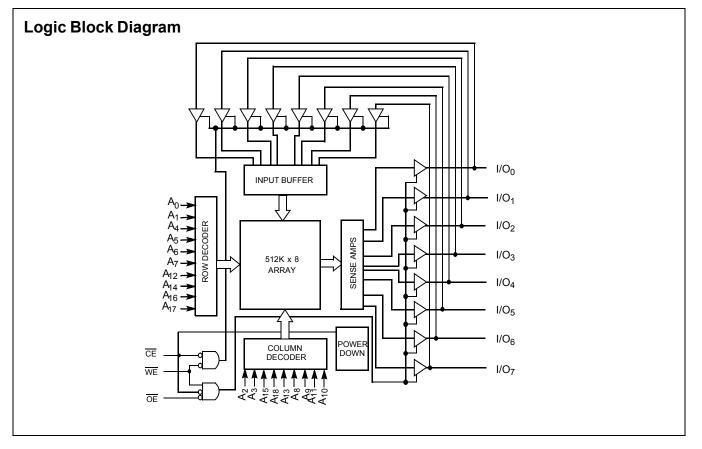
Functional Description

The CY62148BN is a high performance CMOS static RAM organized as 512K words by 8 bits. Easy memory expansion is provided by an <u>active LOW</u> Chip Enable (CE), an active LOW Output Enable (OE), and tri-state drivers. This device has an automatic power down feature that reduces power consumption by more than 99% when deselected.

To write to the device, take Chip Enable ($\overline{\text{CE}}$) and Write Enable ($\overline{\text{WE}}$) inputs LOW. Data on the eight I/O pins (I/O₀ through I/O₇) is then written into the location specified on the address pins (A₀ through A₁₈).

To read <u>from</u> the device, take Chip Enable (\overline{CE}) and Output Enable (\overline{OE}) LOW while forcing Write Enable (WE) HIGH for read. Under these conditions, the contents of the memory location specified by the address pins appear on the I/O pins.

The eight input/output pins $(I/O_0 \text{ through } I/O_7)$ <u>go</u> into a high-impedance state whe<u>n the</u> device is deselected (CE HIGH), the output<u>s a</u>re disabled (OE HIGH), or a write operation is in progress (CE LOW and WE LOW).



198 Champion Court

San Jose, CA 95134-1709 • 408-943-2600 Revised June 7, 2010 [+] Feedback



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Pin Configuration

	Top Vi SOIC TSOI	•
A17 A16 A14 A12 A17 A14 A12 A14 A12 A14 A14 A12 A14 A14 A14 A14 A14 A14 A14 A14 A14 A14	1 O 2 3 4 5 6 7 8 9 10 11 12	$\begin{array}{c c} 32 & \lor V_{CC} \\ 31 & \land 15 \\ 30 & \land 418 \\ 29 & \lor WE \\ 28 & \land 413 \\ 27 & \land 8 \\ 26 & \land 49 \\ 25 & \land 411 \\ 02 & \land 612 \\ 23 & \land 410 \\ 22 & \land CE \\ 21 & \lor 107 \\ 22 & \land CE \\ 21 & \lor 107 \\ 22 & \land CE \\ 21 & \lor 107 \\ 22 & \land CE \\ 21 & \lor 107 \\ 22 & \land CE \\ 21 & \lor 107 \\ 22 & \land CE \\ 21 & \lor 107 \\ 22 & \land CE \\ 21 & \lor 107 \\ 22 & \land CE \\ 21 & \lor 107 \\ 22 & \land CE \\ 21 & \lor 107 \\ 22 & \lor 107 \\ 22 & \lor 107 \\ 23 & \land 107 \\ 24 & \lor $
	13 14 15 16	20 //O ₆ 19 //O ₅ 18 //O ₄ 17 //O ₃

Product Portfolio

		V _{CC} Range			Power Di Operating I _{CC} (mA)		r Dissipation		
Product				Speed			Standby	I _{SB2} (μΑ)	
					f = f _{max}		$\mathbf{f} = \mathbf{f}_{\max} \qquad \mathbf{Typ}^{[1]}$		Мах
	Min	Тур	Max		Typ ^[1]	Max	iyb. ,	IVIAX	
CY62148BNLL	4.5 V	5.0V	5.5V	70 ns	12.5	20	4	20	

Note 1. Typical values are measured at V_{CC} = 5V, T_A = 25 C, and are included for reference only and are not tested or guaranteed.



CY62148BN MoBL[®]

Maximum Ratings

Exceeding the maximum rating may impair the device's useful life. User guidelines only and are not tested.

Storage Temperature65 C to +150 C	
Ambient Temperature with Power Applied55 C to +125 C	
Supply Voltage on V_{CC} to Relative GND–0.5V to +7.0V	
DC Voltage Applied to Outputs in High Z State $^{\left[2\right]}$ 0.5V to V_{CC} +0.5V	

DC Input Voltage ^[2]	–0.5V to V _{CC} +0.5V
Current into Outputs (LOW)	20 mA
Static Discharge Voltage	2001V
(per MIL-STD-883, Method 3015)	
Latch Up Current	>200 mA

Operating Range

Range	Ambient Temperature ^[3]	V _{cc}
Industrial	–40 C to +85 C	4.5V–5.5V

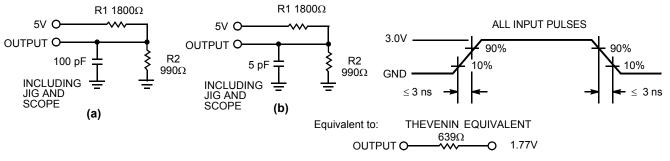
Electrical Characteristics Over the Operating Range

Parameter	Description	n Test Conditions		(CY62148B	N	Unit
Parameter	Description			Min	Typ ^[1]	Max	Unit
V _{OH}	Output HIGH Voltage	I _{OH} = –1 mA		2.4			V
V _{OL}	Output LOW Voltage	I _{OL} = 2.1 mA				0.4	V
V _{IH}	Input HIGH Voltage			2.2		V _{CC} +0.3	V
V _{IL}	Input LOW Voltage			-0.3		0.8	V
I _{IX}	Input Leakage Current	$GND \leq V_I \leq V_{CC}$		–1		+1	μA
I _{OZ}	Output Leakage Current	$GND \leq V_{I} \leq V_{CC}, Ou$	tput Disabled	–1		+1	μA
I _{CC}	V _{CC} Operating	$f = f_{MAX} = 1/t_{RC}$	I _{OUT} = 0 mA		12.5	20	mA
	Supply Current	f = 1 MHz	V _{CC} = Max.,		2.5		mA
I _{SB1}	Automatic CE Power Down Current – TTL Inputs	$\begin{array}{l} \text{Max. } V_{CC}, \ \overline{CE} \geq V_{IH} \\ V_{IN} \geq V_{IH} \ \text{or} \ V_{IN} \leq V_{I} \end{array}$	_L , f = f _{MAX}			1.5	mA
I _{SB2}	Automatic CE Power Down Current – CMOS Inputs	$\begin{array}{l} \text{Max. } V_{CC}, \ \overline{CE} \geq V_{CC} \\ V_{IN} \geq V_{CC} - 0.3 \text{V, or} \end{array}$	y – 0.3V, V _{IN} ≤ 0.3V, f =0		4	20	μA

Capacitance^[4]

Parameter	Description	Test Conditions	Max.	Unit
C _{IN}	Input Capacitance	$T_A = 25$ C, f = 1 MHz,	6	pF
C _{OUT}	Output Capacitance	V _{CC} – 5.0V	8	pF

AC Test Loads and Waveforms



Notes

2. V_{IL} (min.) = -2.0V for pulse durations of less than 20 ns. 3. T_A is the "instant on" case temperature

4. Tested initially and after any design or process changes that may affect these parameters.



Switching Characteristics^[5] Over the Operating Range

Demonstern	Description	CY621	148BN	11
Parameter	Description	Min	Max	– Unit
READ CYCLE			I	
t _{RC}	Read Cycle Time	70		ns
t _{AA}	Address to Data Valid		70	ns
t _{OHA}	Data Hold from Address Change	10		ns
t _{ACE}	CE LOW to Data Valid		70	ns
t _{DOE}	OE LOW to Data Valid		35	ns
t _{LZOE}	OE LOW to Low Z ^[6]	5		ns
t _{HZOE}	OE HIGH to High Z ^[6, 7]		25	ns
t _{LZCE}	CE LOW to Low Z ^[6]	10		ns
t _{HZCE}	CE HIGH to High Z ^[6, 7]		25	ns
t _{PU}	CE LOW to Power Up	0		ns
t _{PD}	CE HIGH to Power Down		70	ns
WRITE CYCLE ^[8]		L.		
t _{WC}	Write Cycle Time	70		ns
t _{SCE}	CE LOW to Write End	60		ns
t _{AW}	Address Setup to Write End	60		ns
t _{HA}	Address Hold from Write End	0		ns
t _{SA}	Address Setup to Write Start	0		ns
t _{PWE}	WE Pulse Width	55		ns
t _{SD}	Data Setup to Write End	30		ns
t _{HD}	Data Hold from Write End	0		ns
t _{LZWE}	WE HIGH to Low Z ^[6]	5		ns
t _{HZWE}	WE LOW to High Z ^[6, 7]		25	ns

Notes

- Test conditions assume signal transition time of 5 ns or less, timing reference levels of 1.5V, input pulse levels of 0 to 3.0V, and output loading of the specified I_{OL}/I_{OH} and 100-pF load capacitance. At any given temperature and voltage condition, t_{HZCE} is less than t_{LZCE} , t_{HZOE} is less than t_{LZOE} , and t_{HZWE} is less than t_{LZWE} for any given device. t_{HZOE} , t_{HZCE} , and t_{HZWE} are specified with a load capacitance of 5 <u>pF</u> as in part (<u>b) of</u> AC Test Loads. Transition is measured ±500 mV from steady-state voltage. The internal write time of the memory is defined by the overlap of CE LOW, and WE LOW. CE and WE must be LOW to initiate a write, and the transition of any of these signals can terminate the write. The input data setup and hold timing should be referenced to the leading edge of the signal that terminates the write. 5.
- 6.

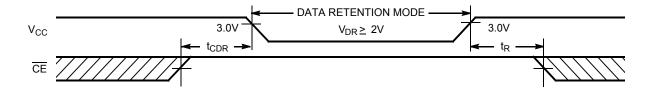
7. 8.



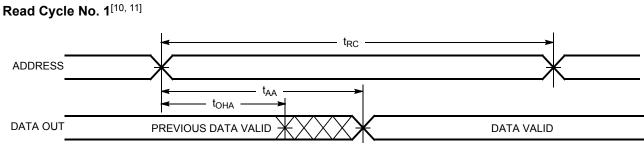
Data Retention Characteristics (Over the Operating Range)

Parameter	Description	Conditions	Min	Typ ^[1]	Max	Unit
V _{DR}	V _{CC} for Data Retention		2.0			V
I _{CCDR}	Data Retention Current	No input may exceed			20	μA
t _{CDR} ^[4]	Chip Deselect to Data Retention Time	$V_{CC} + 0.3V$ $V_{CC} = V_{DR}$	0			ns
t _R [9]	Operation Recovery Time	$\frac{V_{CC}}{CE} = V_{DR}$ $\frac{CE}{CE} > V_{CC} - 0.3V$ $\frac{V_{IN}}{V_{IN}} > V_{CC} - 0.3V \text{ or } V_{IN} < 0.3V$	t _{RC}			ns

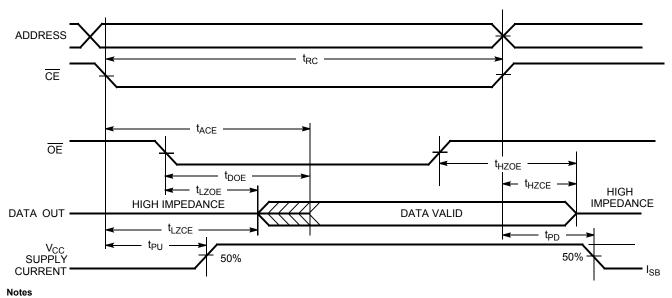
Data Retention Waveform



Switching Waveforms



Read Cycle No. 2 (OE Controlled)^[11, 12]



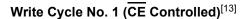
Full Device operation requires linear V_{CC} ramp from V_{DR} to V_{CC(min)} ≥ 100 ms or stable at V_{CC(min)} ≥ 100 ms. <u>Dev</u>ice is continuously selected. OE, CE = V_{IL}.

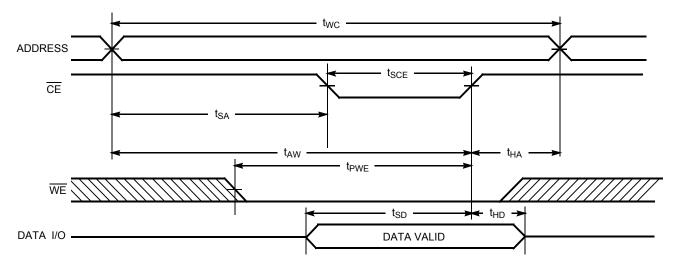
11. WE is HIGH for read cycle.

12. Address valid prior to or coincident with $\overline{\text{CE}}$ transition LOW.

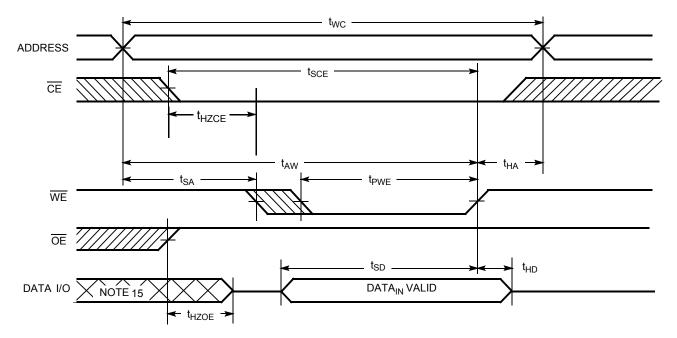


Switching Waveforms (continued)





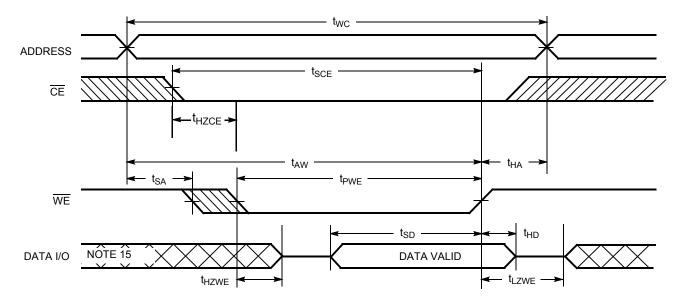
Write Cycle No. 2 (WE Controlled, OE HIGH During Write)^[13, 14]





Switching Waveforms (continued)

Write Cycle No. 3 ($\overline{\text{WE}}$ Controlled, $\overline{\text{OE}}$ LOW)^[13, 14]



Truth Table

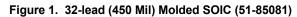
CE	OE	WE	I/O ₀ –I/O ₇	Mode	Power
Н	Х	Х	High Z	Power Down	Standby (I _{SB})
L	L	Н	Data Out	Read	Active (I _{CC})
L	Х	L	Data In	Write	Active (I _{CC})
L	Н	Н	High Z	Selected, Outputs Disabled	Active (I _{CC})

Ordering Information

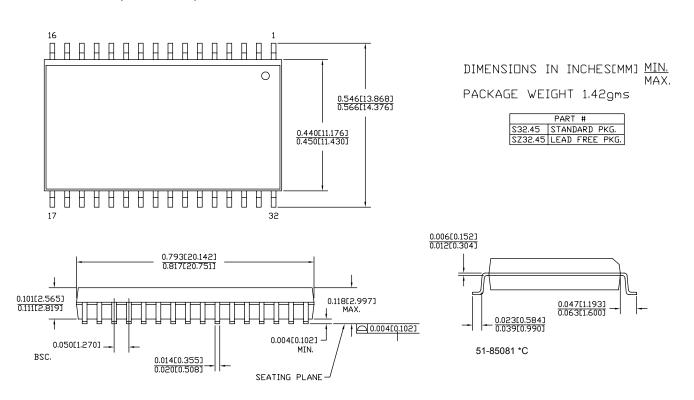
Speed (ns)	Ordering Code	Package Diagram	Package Type	Operating Range
70	CY62148BNLL-70SXI	51-85081	32-lead (450-Mil) Molded SOIC (Pb-Free)	Industrial



Package Diagram



32 LD (450 Mil) SOIC



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Document History Page

Document Title: CY62148BN MoBL [®] 4-Mbit (512K x 8) Static RAM Document Number: 001-06517						
REV.	ECN NO.	Issue Date	Orig. of Change	Description of Change		
**	426504	See ECN	NXR	New Data Sheet		
*A	485639	See ECN	VKN	Corrected the typo in the Array size in the Logic Block Diagram		
*В	832320	See ECN	NXR	Removed Commercial Operating Range Removed 32-lead Reverse TSOP II package from product offering Corrected the test condition typo error in Electrical Characteristics table Updated Ordering information table		
*C	2896152	03/18/2010	AJU	Removed inactive parts from Ordering Information. Added Table of Contents. Updated Packaging Information Updated links in Sales, Solutions, and Legal Information.		
*D	2946367	06/07/2010	FSU	Removed unavailable parts.		

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